

Workshop on Memory Testing, San Jose, CA, ... Records of the 1993 IEEE International Workshop on Memory Testing, San Jose,. Segmentation: a technique for adapting high-performance logic ATE . Records of the 1993 IEEE International Workshop on Memory Testing, August 9-10, 1993, San Jose, California. edited by R. Rajsuman ; sponsored by IEEE ... Records of the 1993 IEEE International Workshop on Memory . Records of the 1993 IEEE International Workshop on Memory Testing August 9-10, 1993 San Jose, California [Rochit Rajsuman] on Amazon.com. *FREE* ... An optimal march test for locating faults in DRAMs Cell array faults in random-access memories (RAMs) are usually represented . fault pattern-sensitive fault RAM semilattice stuck-at fault testing transition fault. Records of the 1993 IEEE International Workshop on Memory . From the August 1993 workshop in San Jose, California, 26 papers report the latest . The sections include test pattern generation, algorithms, fault models, testing for ... Workshop on Memory Testing, August 9-10, 1993, San Jose, California. Records of the 1993 IEEE International Workshop on Memory . Records of the 1993 IEEE International Workshop on Memory Testing August 9-10, 1993 San Jose, California von R. Rajsuman von IEEE Computer Society ... Patente US5506959 - Method and apparatus for testing electronic . Memory Testing, 1993., Records of the 1993 IEEE International Workshop on. Date of Conference: 9-10 Aug 1993. Page(s): 38 - 43 ... Number: 4565553. Conference Location : San Jose, CA; DOI: 10.1109/MT.1993.263152; Publisher: IEEE ... Records of the 1993 IEEE international Workshop on memory . Records of the 1993 IEEE International Workshop on Memory Testing, August 9-10, 1993, San Jose, California by Rochit Rajsuman, IEEE Computer Society. IEEE Xplore Abstract - Effective tests for memories based on faults . Records of the 1993 IEEE International Workshop on Memory Testing, August 9-10, 1993, San Jose, California. n/a. Published by IEEE Computer Society Press, ... Records of the 1993 IEEE International Workshop on Memory .

{/REPLACEMENT}